## WHAT IS CLAIMED IS:

- 1. An SRAM device, comprising:
- an SRAM array coupled to row peripheral circuitry by a word
- 3 line and coupled to column peripheral circuitry by bit lines; and
- 4 an array low voltage control circuitry that provides an
- 5 enhanced low operating voltage  $V_{\text{ESS}}$  to said SRAM array during at
- 6 least a portion of an active mode thereof.
- 2. The SRAM device as recited in Claim 1 wherein said array
- 2 low voltage control circuitry provides said enhanced low operating
- 3 voltage  $V_{\text{ESS}}$  only during a WRITE operation.
  - 3. The SRAM device as recited in Claim 1 wherein said array
- 2 low voltage control circuitry provides said enhanced low operating
- 3 voltage  $V_{\mbox{\scriptsize ESS}}$  during all of said active mode.
- 4. The SRAM device as recited in Claim 1 wherein said array
- 2 low voltage control circuitry provides said enhanced low operating
- 3 voltage  $V_{ESS}$  during all modes.

- 5. The SRAM device as recited in Claim 1 wherein said array
- 2 low voltage control circuitry provides said enhanced low operating
- 3 voltage  $V_{\text{ESS}}$  based on a factor selected from the group consisting
- 4 of:
- 5 a process corner,
- 6 a transistor parameter,
- 7 a mode of operation, and
- a value of a high supply voltage.
- 6. The SRAM device as recited in Claim 1 wherein said array
- 2 low voltage control circuitry provides said enhanced low operating
- 3 voltage  $V_{\text{ESS}}$  at a higher value when based on a strong n process
- 4 corner.
- 7. The SRAM device as recited in Claim 1 wherein said array
- 2 low voltage control circuitry provides said enhanced low operating
- 3 voltage  $V_{\text{ESS}}$  at a lower value during a READ operation than during a
- 4 WRITE operation.
- 8. The SRAM device as recited in Claim 7 wherein said array
- 2 low voltage control circuitry only provides said lower value for an
- 3 addressed column of said SRAM array.

- 9. The SRAM device as recited in Claim 1 wherein said array
- 2 low voltage control circuitry employs an active component to
- 3 provide said enhanced low operating voltage  $V_{\text{ESS}}$ .
- 10. The SRAM device as recited in Claim 1 wherein said array
- 2 low voltage control circuitry provides said enhanced low operating
- 3 voltage  $V_{\text{ESS}}$  employing a component selected from the group
- 4 consisting of:
- 5 a diode,
- 6 a transistor,
- 7 a fuse,
- 8 a ROM,
- 9 a voltage regulator, and
- 10 logic circuitry.
  - 11. The SRAM device as recited in Claim 1 wherein said array
- 2 low voltage control circuitry provides said enhanced low operating
- 3 voltage  $V_{\text{ESS}}$  at a higher value than a low operating voltage  $V_{\text{SS}}$ .

- 12. A method of operating an SRAM device, comprising:
- 2 employing in an integrated circuit an SRAM array coupled to
- 3 row peripheral circuitry by a word line and coupled to column
- 4 peripheral circuitry by bit lines; and
- providing an enhanced low operating voltage  $V_{\text{ESS}}$  to said SRAM
- 6 array during at least a portion of an active mode.
- 13. The method as recited in Claim 12 wherein said providing
- only occurs during a WRITE operation.
- 14. The method as recited in Claim 12 wherein said providing
- 2 occurs during all of said active mode.
- 15. The method as recited in Claim 12 wherein said providing
- 2 occurs during all modes.
  - 16. The method as recited in Claim 12 wherein said providing
- 2 is based on a factor selected from the group consisting of:
- 3 a process corner,
- 4 a transistor parameter,
- 5 a mode of operation, and
- 6 a value of a high supply voltage.

- 17. The method as recited in Claim 12 wherein said enhanced
- low operating voltage  $V_{\text{ESS}}$  is provided at a higher value based on
- 3 a strong n process corner.
- 18. The method as recited in Claim 12 wherein said enhanced
- low operating voltage  $V_{\text{ESS}}$  is provided at a lower value during a
- 3 READ operation than during a WRITE operation.
- 19. The method as recited in Claim 18 wherein said lower
- value is only provided for an addressed column of said SRAM array.
  - 20. The method as recited in Claim 12 wherein said providing
- 2 includes employing an active component to provide said enhanced low
- 3 operating voltage  $V_{ESS}$ .
- 21. The method as recited in Claim 12 wherein said providing
- 2 includes employing a component selected from the group consisting
- 3 of:

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- 4 a diode,
- 5 a transistor,
- 6 a fuse,
- 7 a ROM,
- 8 a voltage regulator, and
- 9 logic circuitry.